

## 1. Description

### ➤ Advantages

BLQG3043 is obtained by advanced ignition IGBTs technology which reduce the conduction loss, enhance the SCIS capability. Internally integrated diodes can provide the voltage clamping without the need for external components. The IGBT is suitable device for automotive ignition circuits, specifically as a coil driver.

### ➤ Key Characteristics

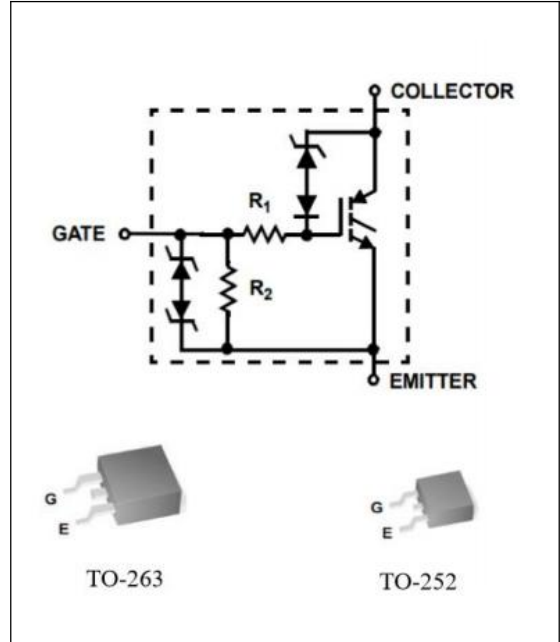
Parameter	Value	Unit
$V_{CES,Typ}$	425	V
$V_{CE(sat),Typ}$	1.25	V
$E_{SCIS}@T_J=25\text{ }^\circ\text{C}$	300	mJ
ESD	4	kV

### ➤ Features

- Low  $V_{CEsat}$
- High SCIS Energy
- Logic Level Gate Drive
- AEC-Q101 Qualified

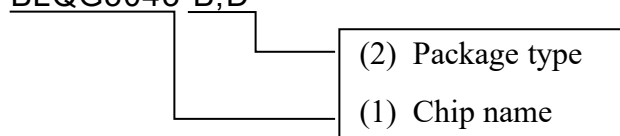
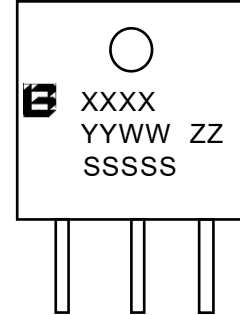
### ➤ Applications

- Automotive ignition Coil Driver Circuits
- Coil-On Plug Application



### ➤ Ordering Informations

Ordering Codes	Package	Product Code	Packing
BLQG3043-D	TO-252	QG3043	Tape Reel
BLQG3043-B	TO-263		Tape Reel

<p>BLQG3043-B,D</p>  <p>(1) BLQG3043:425V 300mJ                  (2) B:TO-263 D:TO-252</p>	 <p>XXXX: Product Code                  YYWW: Year &amp; Week                  ZZ: Assembly Code                  SSSSS: Lot Code</p>
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## 2. Absolute Ratings

at  $T_C = 25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter	Rating	Units
$V_{CES}$	Collector-Emitter Voltage ( $I_C=2\text{mA}$ , $R_G=1\text{k}\Omega$ )	455	V
$V_{ECS}$	Emitter to Collector Voltage ( $I_C=10\text{mA}$ )	24	V
$E_{SCIS}$	SCIS Energy@ $T_J=25^\circ\text{C}$ , $I_{SCIS}=14.2\text{A}$	300	mJ
	SCIS Energy@ $T_J=150^\circ\text{C}$ , $I_{SCIS}=10.6\text{A}$	170	mJ
$I_C$	Collector Current @ $T_C=25^\circ\text{C}$	21	A
	Collector Current @ $T_C=100^\circ\text{C}$	17	A
ESD	Electrostatic Discharge Voltage (HBM) at 100pF, 1500 $\Omega$	4	kV
$V_{GEM}$	Gate- Emitter Voltage Continuous	$\pm 10$	V
$P_D$	Power Dissipation @ $T_C = 25^\circ\text{C}$	150	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	-40 to 175	$^\circ\text{C}$
$T_L$	Maximum Temperature for Soldering	260	$^\circ\text{C}$

## 3. Thermal Characteristics

Symbol	Parameter	Package	RATINGS	Units
$R_{\theta JC}$	Junction-to-Case	TO-252/TO-263	1.0	$^\circ\text{C} / \text{W}$

## 4. Electrical Characteristics

at  $T_C = 25^\circ\text{C}$ , unless otherwise specified

OFF Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$BV_{CER}$	Collector to Emitter Breakdown Voltage	$V_{GE}=0\text{V}$ , $I_C=2\text{mA}$ , $R_G=1\text{k}\Omega$	395	425	455	V
$BV_{CES}$	Collector to Emitter Breakdown Voltage	$V_{GE}=0\text{V}$ , $I_C=10\text{mA}$ , $R_G=0\Omega$	410	440	470	V
$BV_{ECS}$	Emitter to Collector Breakdown Voltage	$V_{GE}=0\text{V}$ , $I_C=-75\text{mA}$	30	--	--	V
$BV_{GES}$	Gate to Emitter Breakdown Voltage	$I_{GES}=\pm 2\text{mA}$	$\pm 12$	$\pm 14$		V
$I_{CER}$	Collector to Emitter Leakage Current	$V_{CE}=250\text{V}$ , $R_G=1\text{k}\Omega$ , $T_J=25^\circ\text{C}$	--	--	25	$\mu\text{A}$
		$V_{CE}=250\text{V}$ , $R_G=1\text{k}\Omega$ , $T_J=150^\circ\text{C}$	--	--	1	mA
$I_{ECS}$	Emitter to Collector Leakage Current	$V_{EC}=24\text{V}$ , $T_J=25^\circ\text{C}$	--	--	1	mA
		$V_{EC}=24\text{V}$ , $T_J=150^\circ\text{C}$			40	mA

$R_1$	Series Gate Resistance	--	70	$\Omega$
$R_2$	Gate to Emitter Resistance	10	26	k $\Omega$

### ON Characteristics

Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE}=4V, I_C=6A, T_J=25^\circ C$	--	1.20	1.60	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE}=4.5V, I_C=10A, T_J=175^\circ C$	--	1.52	1.80	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE}=4.5V, I_C=15A, T_J=175^\circ C$	--	1.90	2.20	V
$V_{GE(TH)}$	Gate Threshold Voltage	$V_{CE} = V_{GE}, I_C = 1mA$	1.30	--	2.20	V

Pulse width  $t_p \leq 300\mu s, \delta \leq 2\%$

### Dynamic Characteristics

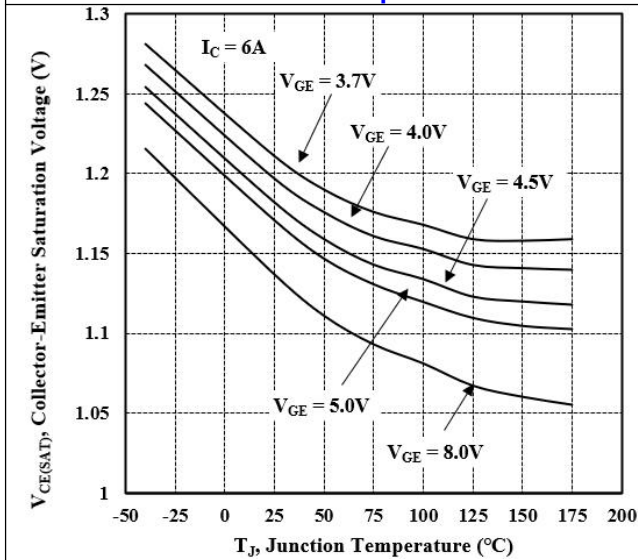
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$C_{iss}$	Input Capacitance	$V_{GE} = 0V$ $V_{CE} = 25V$ $f=1.0MHz$	--	1250	--	pF
$C_{oss}$	Output Capacitance		--	69	--	
$C_{rss}$	Reverse Transfer Capacitance		--	15	--	
$Q_g$	Total Gate Charge	$I_C=10A, V_{CE}=12V, V_{GE}=5V$	--	7.2	--	nC

### Switching Characteristics

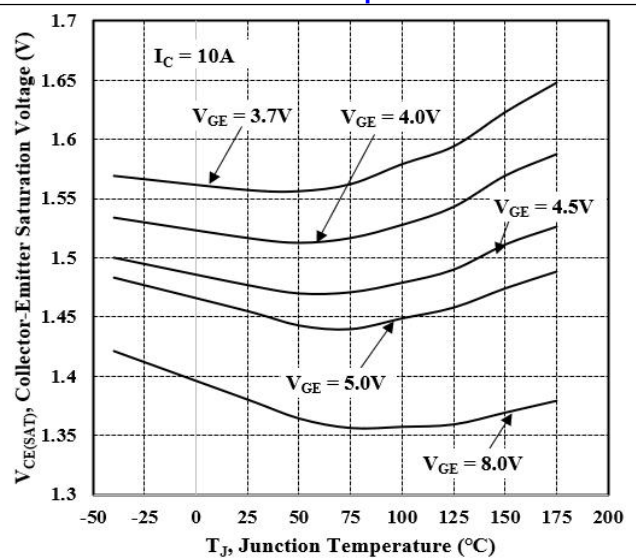
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$V_{CE} = 14V, R_L=1\Omega,$ $V_{GE} = 5V, R_G = 1k\Omega,$ $T_J=25^\circ C$	--	0.85	4	$\mu s$
$t_r$	Rise Time		--	2.50	7	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{CE} = 300V, L=500\mu H,$ $V_{GE} = 5V, R_G = 1k\Omega,$ $T_J=25^\circ C$	--	4.40	15	
$t_f$	Fall Time		--	1.90	15	

## 5. Characteristics Curves

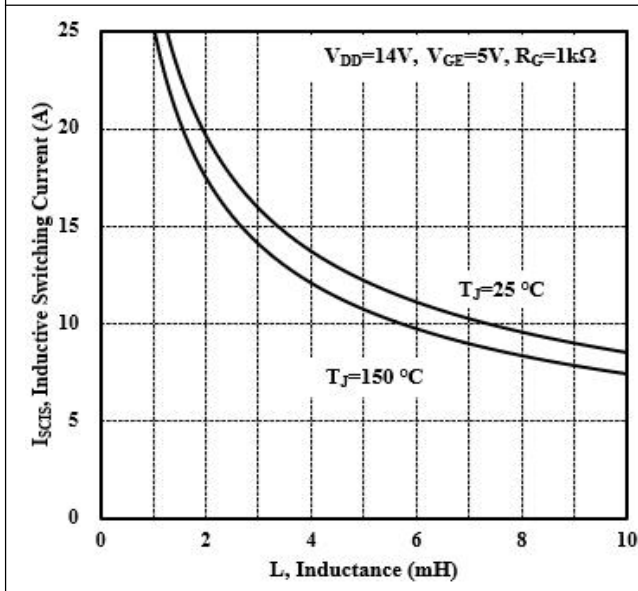
**Figure 1 Collector-Emitter Saturation Voltage vs Junction Temperature**



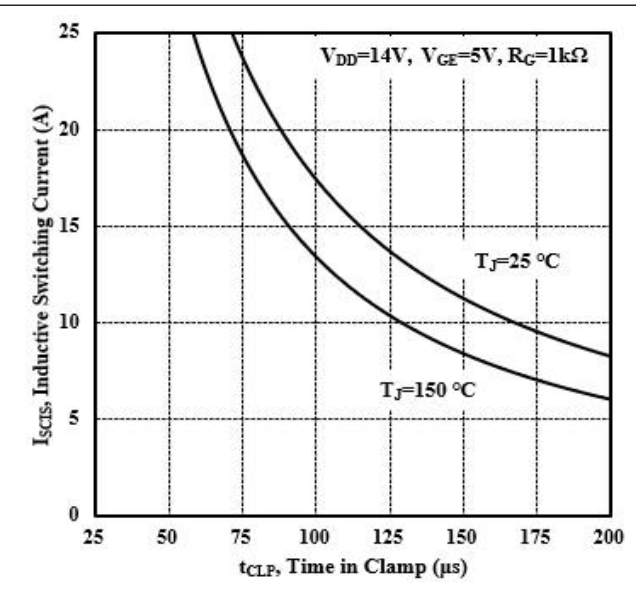
**Figure 2 Collector-Emitter Saturation Voltage vs Junction Temperature**



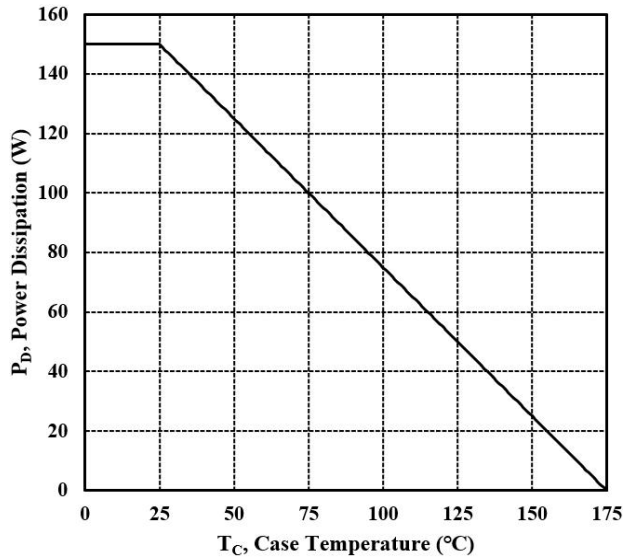
**Figure 3 Self Clamped Inductive Switching Current vs Inductance**



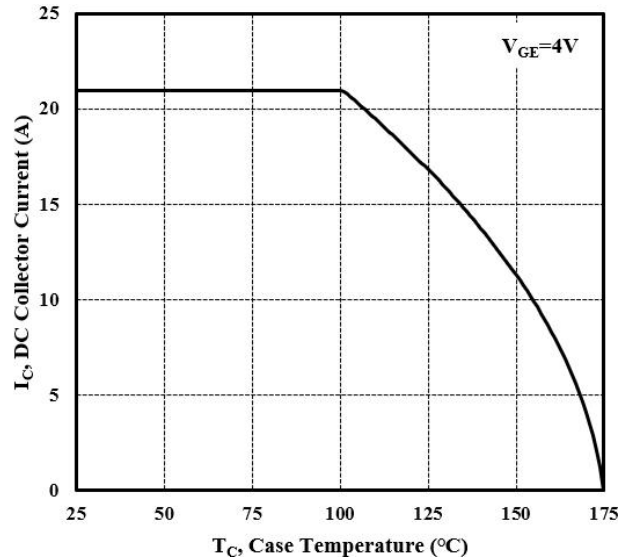
**Figure 4 Self Clamped Inductive Switching Current vs Inductance**



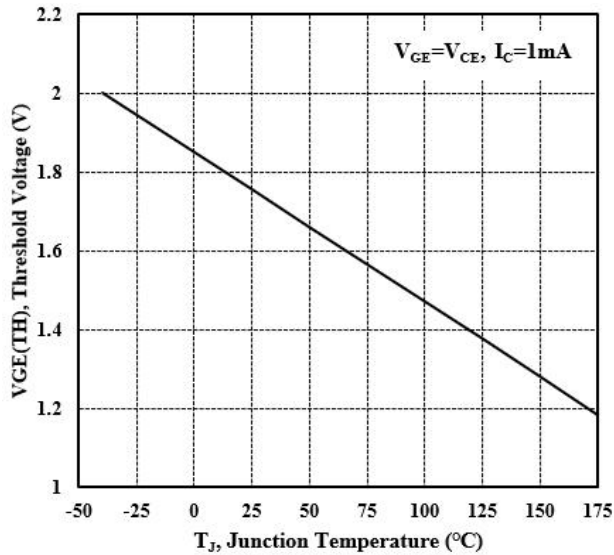
**Figure 5 Power Dissipation vs Case Temperature**



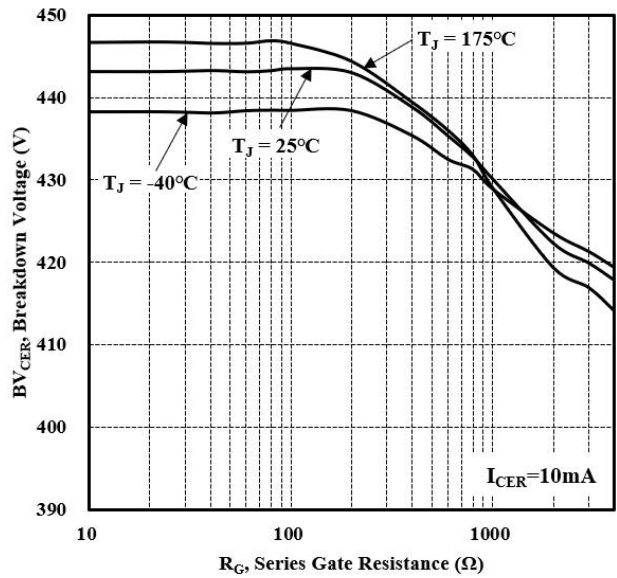
**Figure 6. DC Collector Current vs Case Temperature**



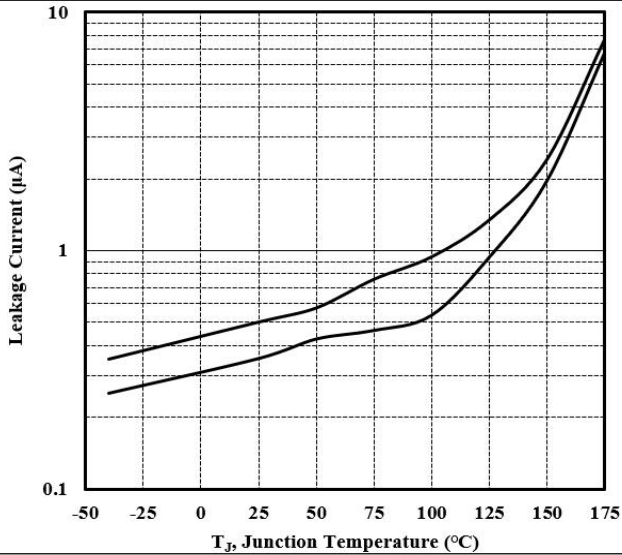
**Figure 7 Threshold Voltage vs Junction Temperature**



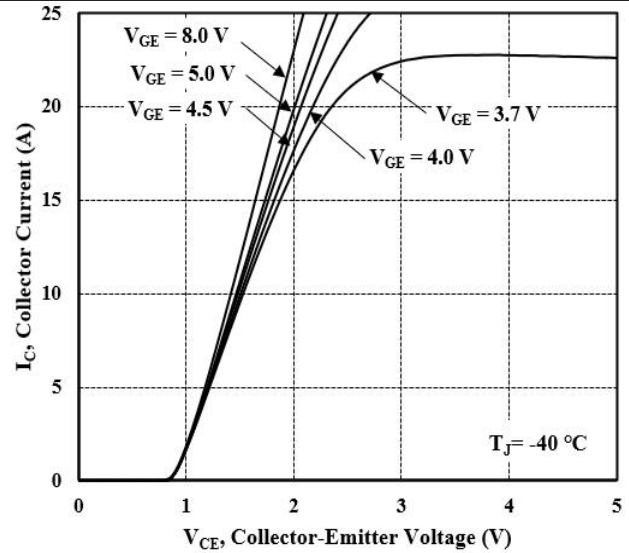
**Figure 8 Breakdown Voltage vs Series Gate Resistance**



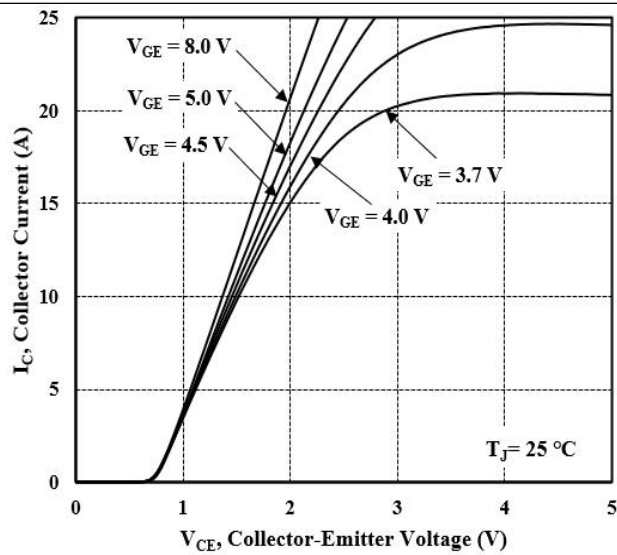
**Figure 9 Leakage Current vs Junction Temperature**



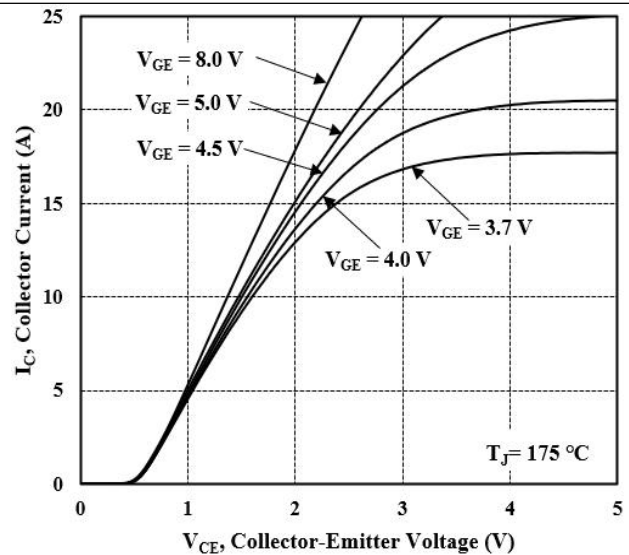
**Figure 10 Collector-Emitter Voltage vs Collector Current**



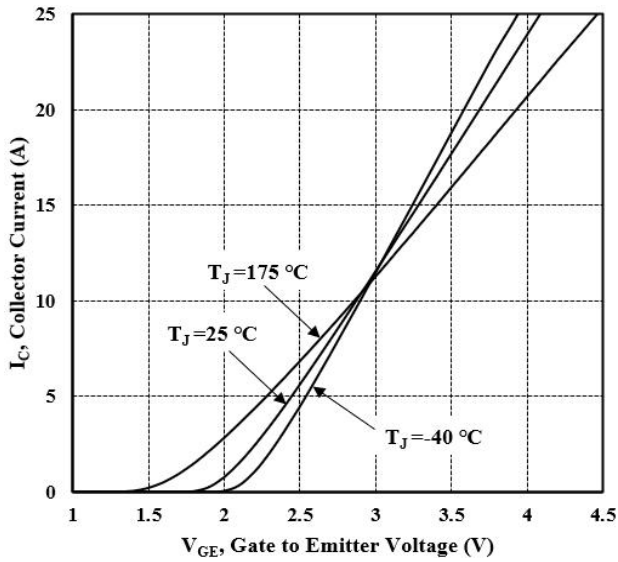
**Figure 11 Collector-Emitter Voltage vs Collector Current**



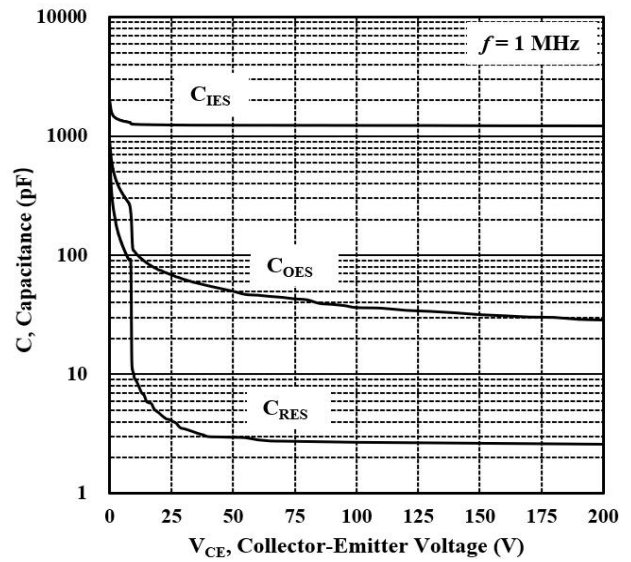
**Figure 12 Collector-Emitter Voltage vs Collector Current**



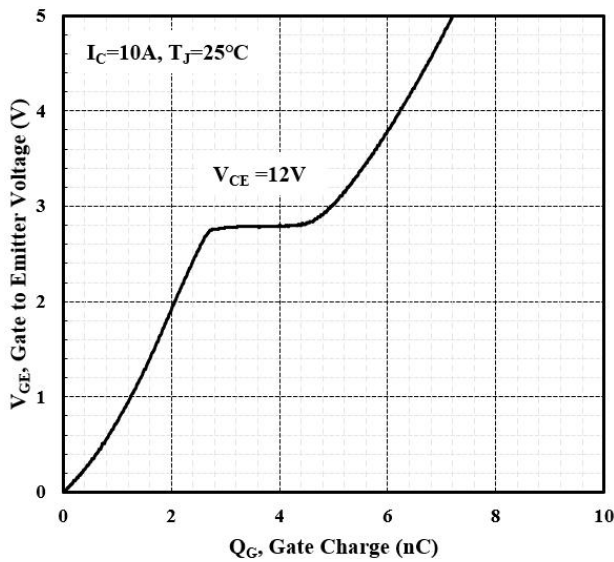
**Figure 13 Transfer Characteristics**



**Figure 14 Capacitance vs Collector to Emitter Voltage**



**Figure 15 Gate Charge vs Gate to Emitter Voltage**



**Figure 16 Switching Time vs Junction Temperature**

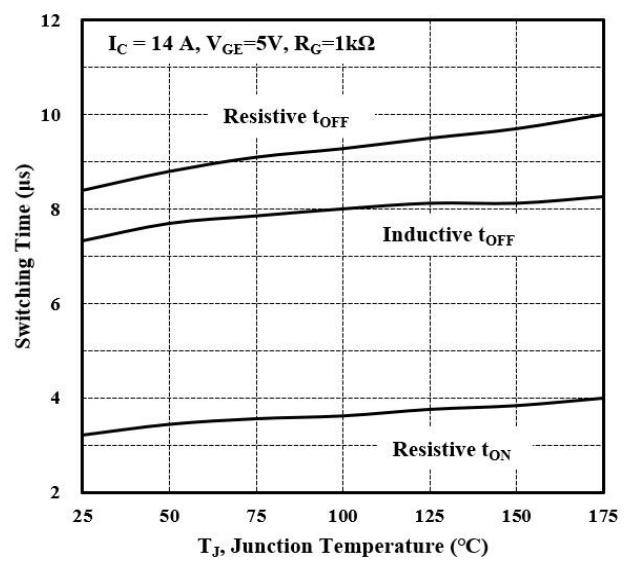
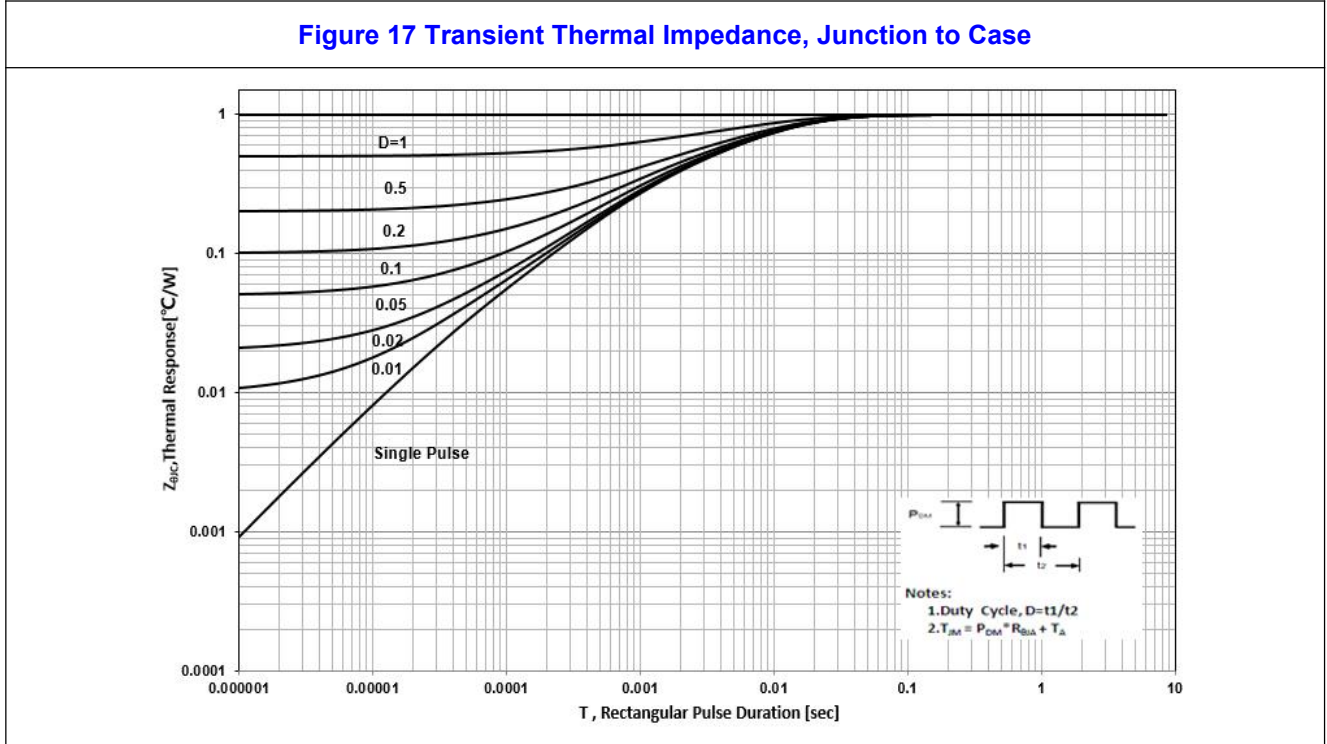


Figure 17 Transient Thermal Impedance, Junction to Case





## 6. Test Circuit and Waveform

Figure 18 Inductive Switching Test Circuit

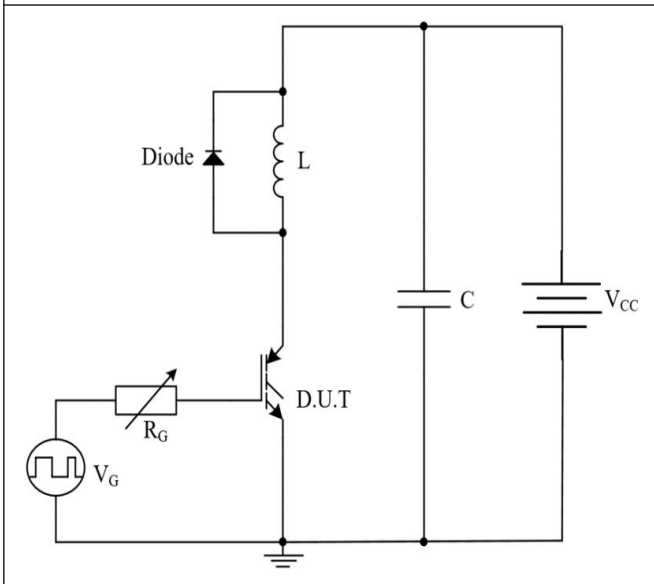


Figure 19 Resistive Switching Test Circuit

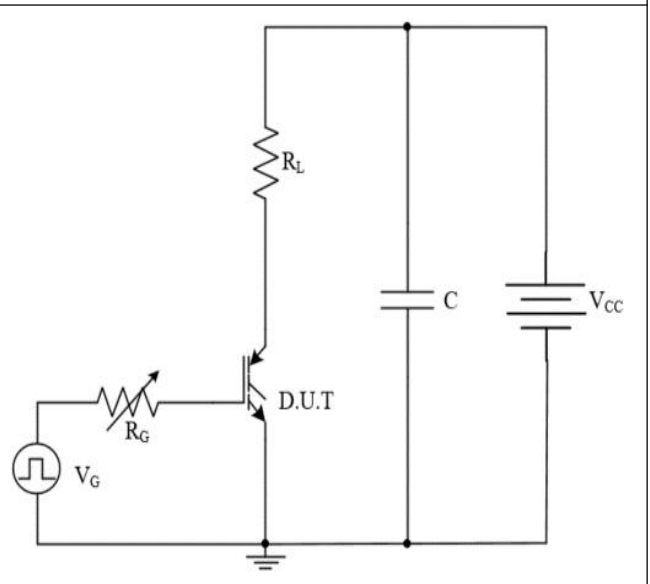


Figure 20 Switching Waveforms

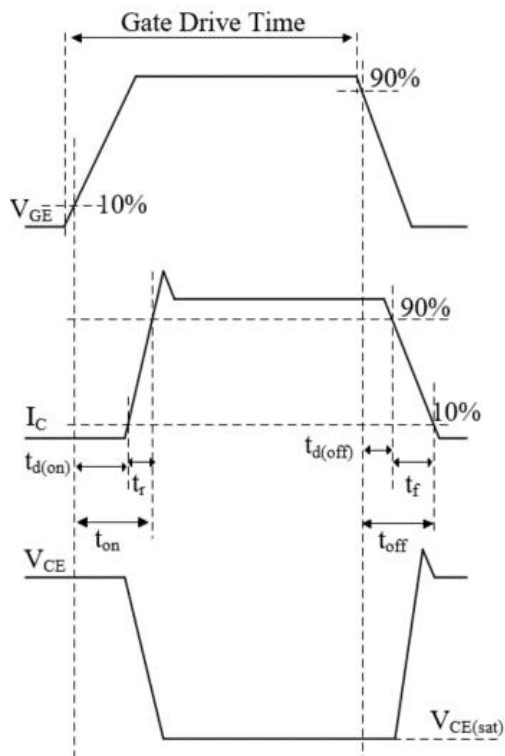


Figure 21 Self Clamped Inductive Switching Circuit

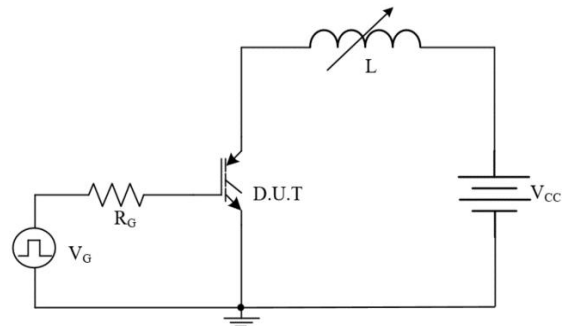
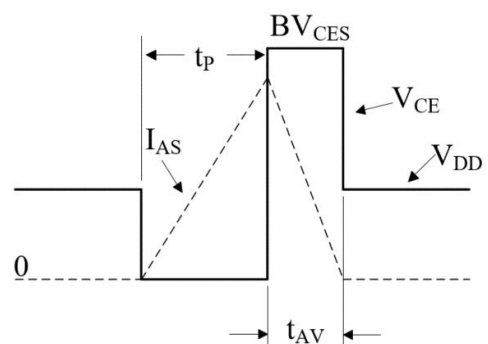
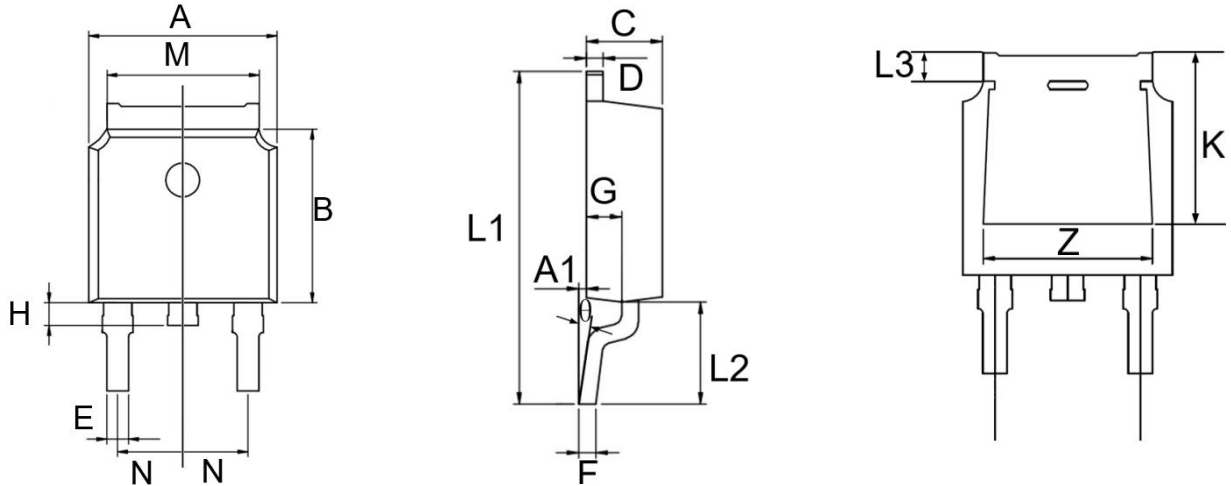


Figure 22 Self Clamped Inductive Switching Waveform

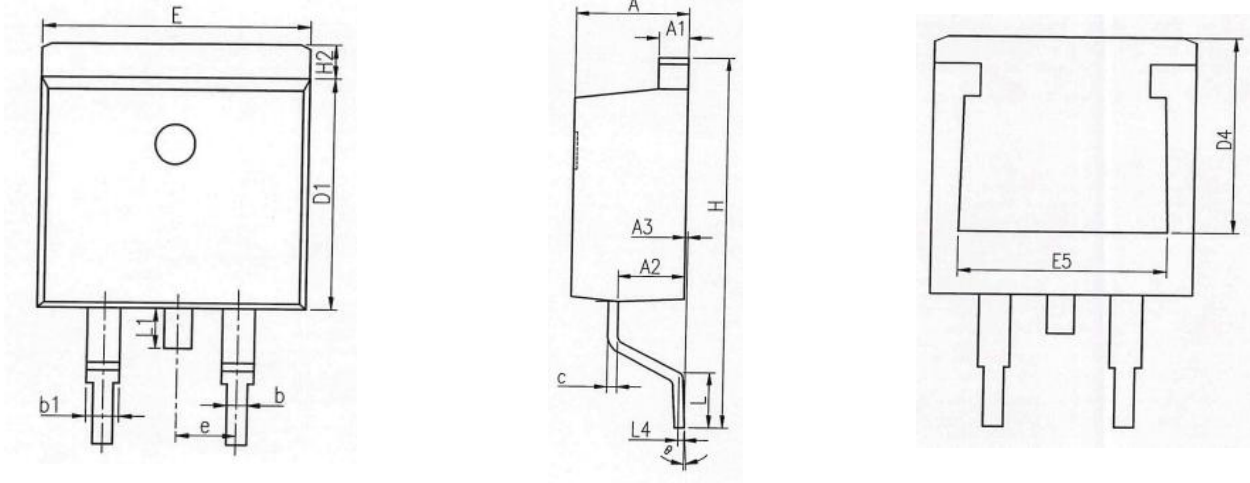


## 7. Package Description



TO-252 Package

Items	Values(mm)		
	MIN	NOM	MAX
A	6.45	6.60	6.75
A1	0.05	0.10	0.20
B	5.95	6.10	6.25
C	2.15	2.30	2.45
D	0.40	0.50	0.60
E	0.66	0.76	0.86
F	0.40	0.500	0.6
G	0.91	1.07	1.22
H	0.60	0.80	1.00
K	3.80		
L1	9.80	10.10	10.40
L2	2.80	3.10	3.40
L3	0.70	0.80	1.00
H	0.60	0.80	1.00
M	5.12	5.32	5.52
2N	4.57		
Z	4.80		
$\theta$	0°	-	8°



**TO-263 Package**

Items	Values (mm)		
	MIN	NOM	MAX
A	4.37	4.57	4.77
A1	1.22	1.27	1.42
A2	2.49	2.69	2.89
A3	0.00	0.13	0.25
b	0.70	0.81	0.96
b1	1.17	1.27	1.47
c	0.30	0.38	0.53
D1	8.50	8.70	8.90
D4	6.60	-	-
E	9.86	10.16	10.36
E5	7.06	-	-
e	2.54 BSC		
H	14.70	15.10	15.50
H2	1.07	1.27	1.47
L	2.00	2.30	2.60
L1	1.40	1.55	1.70
L4	0.25 BSC		
θ	0°	5°	9°

## Revision History:

BLQG3043 Revision: 2024-08-16, Rev. 2.5  
 Previous Revision

Revision	Date	Revision Date Subjects (major changes since last revision)
1.0	2019-10-21	-
1.1	2021-07-06	Some key Information has been added below. (1) Switching characteristics. (2) Self-clamped Inductive switching current curves. (3) Breakdown voltage curves have been added.
2.0	2022-03-31	The major changes are as follow. (1) In Section 4, the data of ON characteristics and dynamic characteristics have been updated. (2) In Section 5, $P_D$ vs $T_J$ curve and $I_{SCIS}$ vs $T_{CLP}$ curve have been added. (3) In Section 5, all figures of characteristics curves have been reformatted and adjusted in sequence. (4) In Section 6, all figures of test circuit and typical waveform have been redrawn and rearranged. (5) In Section 7, all diagrams of different package and some dimensions information have been redrawn and updated. (6) Formatting and spelling errors in this document have been corrected. (7) Revision history is firstly added in the BLG3040 datasheet .
2.1	2022-08-04	(1) The values of breakdown voltage under different test conditions have been updated.
2.2	2022-09-14	(1) The product name has been changed.
2.3	2022-12-23	(1) The minimum value of breakdown voltage under different conditions has been updated . (2) TO-252 package dimensions updated .
2.4	2023-02-27	(1) Add Device Marking . (2) Update TO-263 outline package dimensions.
2.5	2024-08-16	(1) The typical VCES value on the homepage has been changed to 425V. (2) The typical VCE(sat) value on the homepage has been changed to 1.25V. (3) In the 2. Absolute Ratings on the second page, change VCES to 455V. (4) Updated the minimum values for BV <sub>CER</sub> and BV <sub>CES</sub> . (5) Updated the contact information on the last page.

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**NOTE:**

1. Any use beyond the maximum ratings of the device in performance may cause damage to the device or even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when designing circuit.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. Semiconductor device is sensitive to the ESD, it is necessary to protect the device from being damaged by the ESD when using it.
4. Shanghai Belling reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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